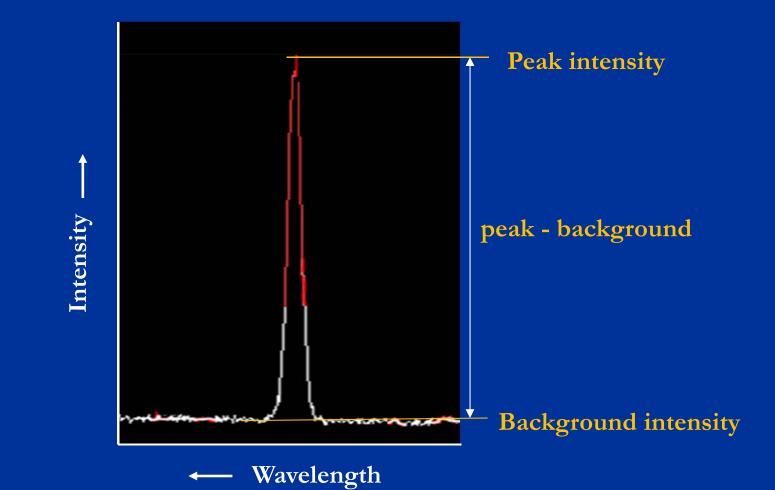
Quantitative Electron Microprobe Analysis Wavelength Dispersive X-ray Spectrometry (WDS)

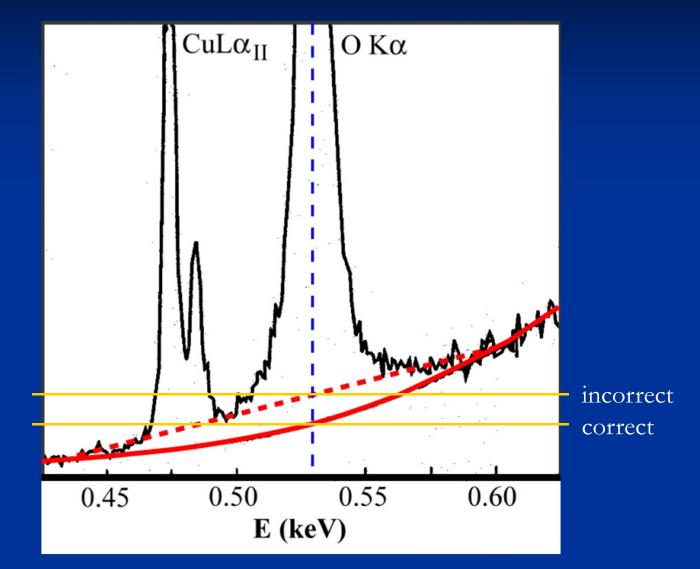
Goal: Measurement of concentration of elements in a microscopic volume

WDS: X-ray intensity measurement



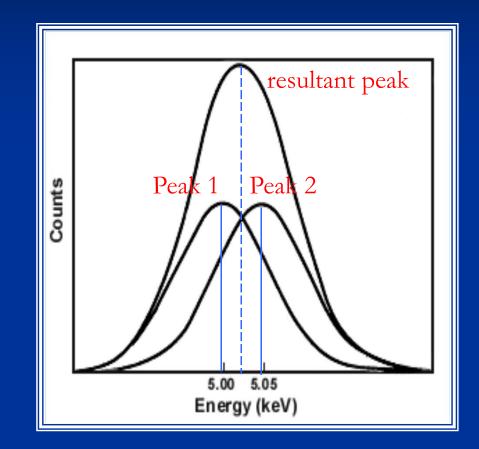
peak minus background intensity

Background modeling in X-ray spectra



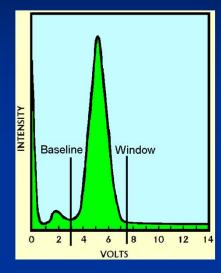
A polynomial fit to the background may be more accurate

Peak overlap in X-ray spectra

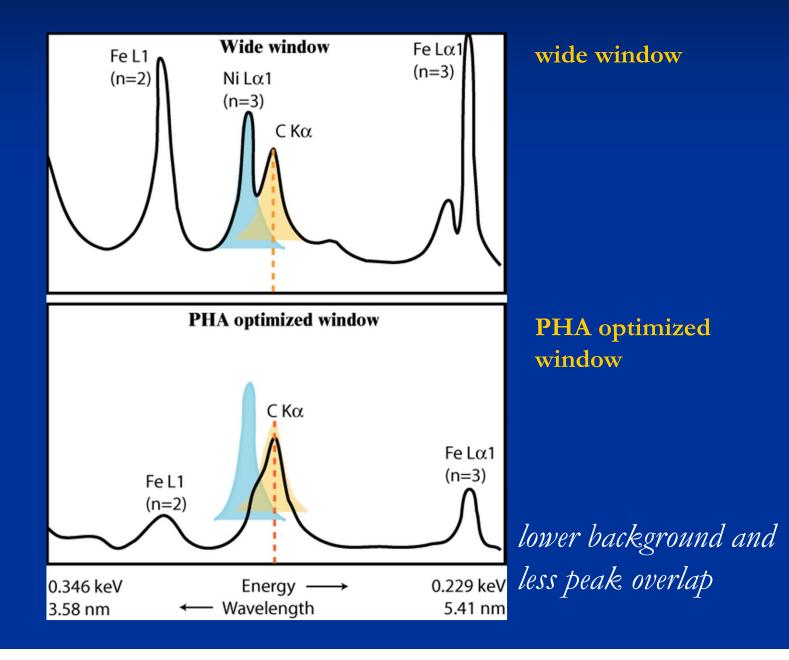


Overlap between Peak 1 and Peak 2 results in a broad single peak

WDS detector optimization with pulse height analysis (PHA)



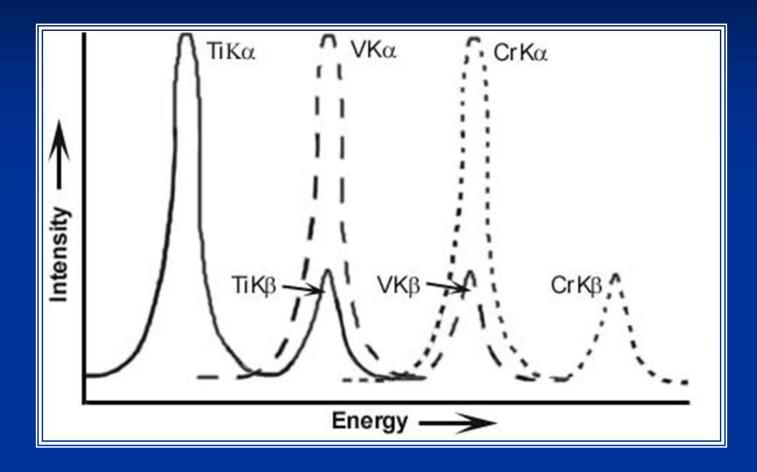
SCA scan

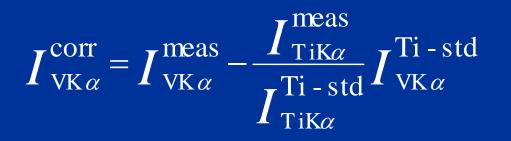


Peak overlap: Kα and Kβ energies (keV) of Ti, V and Cr

Ele- ment	Atm. No.	Ka	Кв()	Kab	to	Lø ₁ (*)	$L\beta_2(\cdot)$	Lγ ₂ (*)	Lilliob	Lillab	Llab	м	Ele- ment	Atm. No.	Ko	Kβ()	Kab	lo	Lβ ₁ (*)	Lβ ₂ (*)	Ly2 (*)	LIIIab	Lillan	Liab	M
LI	3	0.052		0.055			1.1.1.1.1.1.1.1						Cd	48	23.106	26.081(18)		3.133	3.316(42)	3.528(25)	8 13 18	3.537	3.727	4.018	0.606
Be	4	0.109		0.112									In	49	24.136	27.260(18)		3.286	3.487(75)			3.730	3.939	4.237	
B	e a	0.183 0.277		0.192 0.284									Sn Sb	50 51	25.191 26.271	28.467(19) 29.396(19)		3.443 3.604	3.662(75) 3.843(75)			3.928	4.157	4.464	0.691 0.733
N	7	0.392		0.400			•						Te	52	27.468	30.974(19)		3.769	4.029(75)			4.132 4.341	4.381 4.612		0.778
0	8	0.525		0.532				K	ά		Kβ		1	53	28.607	32.272(19)		3.937	4.220(75)			4.558	4.853	5.191	0.110
F	9	0.677		0.687	11	1	22		and the second		1 02	14	Xe	54	29.774	33.600(20)	34.590	4.109	4.420(50)	4.720(20)		4.781	5.103	5.452	
Ne	10	0.848		0.867			22	4.0	508	1	4.93		Cs	55	30.968	34.960(20)		4.286	4.619(50)	4.935(20)		5.011	5.357	5.720	
Na	11	1.041		1.071	1	1	22	10	140		- 40	00	Ba	56	32.188	36.354(21)		4.465	4.827(50)	5.156(20)		5.246	5.622		0.972
Mg Al	12	1.253	/	1.303		(23	4.3	149	1	0.42	0	La Ce	57 58	33.436 34.714	37.771(21) 39.223(21)		4.650 4.839	5.041(50) 5.261(50)	5.383(20) 5.612(20)		5.483 5.723	5.888 6.160	6.267 6.547	0.833
Si	14	1.739	/	1.840	1		24	5.4			- 04	C	Pr	59	36.020	40.771(21)		5.033	5.488(50)			5.962	6.438	6.833	0.005
P	15	2.013	2.139(4)	2.143	L L	1	24	5.4			5.94	0	Nd	60	37.355		43.574	5.229	5.721(50)	6.088(20)		6.208	6.722	7.128	0.978
S	16	2.307	2.465(7)	2.470	1	-	Station Pa		U.130	U.104	0.193	-	Pm	61	38.718		45.198	5.432	5.960(50)	6.338(20)		6.459	7.013	7.434	
CI	17	2.621	2.815(5)	2.819						0.203	0.238		Sm	62	40.111		46.849	5.635	6.204(50)	6.586(20)		6.716	7.312	7.747	1.081
Ar K	18	2.957 3.312	3.190(10)	3.202							0.287		Eu Gd	63 64				5.845 6.056	6.455(50) 6.712(50)	6.842(20)		6.979	7.618	8.059	1.131
Ca	20	3.690	3.589(10) 4.012(10)	3.607 4.037	0.341			/			0.341 0.399		Tb	65				6.272	6.977(50)	7.102(20) 7.365(20)		7.242 7.514	7.930 8.251	8.385 8.715	1.185
Se	21	4.088	4.460(13)		0.395		/				0.355		Dy	66				6.494	7.246(50)	7.634(20)		7.880	8.582	9.050	1.293
TI	22	4.508		4.964	0.452	-					0.530		Ho	67				6.719	7.524(50)	7.910(20)		8.066	8.915	9.398	1.347
V	23	4.949	5.426(13)		0.511				0.512	0.519	0.604		Er	68			-	6.947	7.809(50)	8.188(20)		8.356	9.260	9.756	1.405
Cr Mn	24	5.411	5.946(12)		0.573					0.593	0.742		Tm Yb	69 70				7.179	8.100(50)	8.467(20)	9.424(5)	8.648		10.119	1.462
Fe	25 26	5.894 6.398	6.489(13) 7.057(13)	7.110	0.637					0.650	0.762 0.849		Lu	71			Sec. 1	7.414	8.400(50) 8.708(50)	8.757(20) 9.038(20)	9.778(5) 10.142(6)	8.942 9.247	9.974 10.343	10.489 10.872	1.521 1.581
Co	27	6.924		7.708	0.776						0.929		Hf	72				7.898	9.021(50)	9.346(20)	10.514(10)			11.272	1.644
Ni	28	7.471	8.263(13)		0.851					0.870	1.015		Та	73				8.145	9.342(50)		10.893(10)			11.680	1.709
Cu	29	8.040	8.904(13)	8.979	0.930				0.933	0.953	1.100		W	74				8.396		9.960(20)	11.284(10)	10.198	11.537	12.098	1.774
Zn	30	8.630	9.570(13)		1.012						1.198		Re	75				8.651		10.274(20)				12.529	1.842
Ga Ge	31 32	9.241 9.874	10.262(14)		1.098					1.145	1.303		0s Ir	76 77						10.597(20) 10.919(20)			10000	12.969	1.914
As	33	10.530	10.978(14) 11.722(15)		1.188					1.249	1.413 1.529		Pt	78						11.249(20)			- Construction -	13.421 13.880	1.977
Se	34	11.207	12.494(16)		1.419						1.652		Au	79				9.712	11.440(50)	11.583(20)	13.379(10)	11.919		14.351	2.121
Br	35	11.907	13.286(16)		1.480						1.781		Hg	80				9.987	11.821(50)	11.922(20)	13.828(10)	12.284	and the second se		2.195
Kr	36	12.631	14.107(16)		1.586					1.729	1.916		Ti	81			2.4.6	10.267	12.211(50)	12.270(20)	14.289(10)	12.658		15.340	2.267
Rb	37 38	13.373	14.956(16)		1.694						2.063		Pb Bi	82 83				10.550	12.012(50)	12.621(20)	14.762(10)	13.038			2.342
Sr	39	14.140 14.931	15.830(16) 16.731(17)		1.806						2.217 2.376		Po	84						12.978(20) 13.338(20)				16.373 16.935	2.419
Zr	40	15.744	17.660(18)		2.042	2.124(45)					2.541		AL	85				11.425	13.874(50)	14.065(10)	16.249(10)	14 215		17.490	
Nb	41	16.581	18.729(8)		2.166	2.257(45)					2.710	0.355	Rn	86						14.509(10)				18.058	
Mo	42	17.441	19.599(17)	20.001	2.293	2.394(45)					the state of the s	0.331	Fr	87				12.029	14.768(50)	14.448(20)	17.300(10)	15.028	17.904	18.638	
Tc	43	18.325	20.608(16)		2.424	2.536(45)					3.055		Ra	88				12.338	15.233(50)	14.839(20)	17.845(10)	15.441		19.234	Carlos -
Ru	44 45	19.233	21.646(16)		2.558	2.683(45)	2.004/001					0.461	Ac	89 90				12.650	15./10(50)	15.929(10)	18.405(10)	15.865		19.842	2 004
Rh Pd	22	20.165	22.712(16) 23.806(17) 2		2.696	2.834(40) 2.990(40)	3.001(25) 3.171(25)					0.496	Pa	91				13 288	16, 699(50)	15.621(20) 16.022(20)	10.9/9(10)	16.290	Contra Latin		2.991
Ag		22.101	24.928(17)			3.150(40)	and a state of the					0.552	U	92				13.612	17.217(50)	16.425(20)	20,164(10)	17 162	20.358	21.100	3.165

Peak overlap corrections





$$I_{CrK\alpha}^{corr} = I_{CrK\alpha}^{meas} - \frac{I_{VK\alpha}^{corr}}{I_{VK\alpha}^{V-std}} I_{CrK\alpha}^{V-std}$$

EPMA: Analytical procedure

Sample preparation
Qualitative analysis with EDS
Standard intensity measurement (calibration)
Measurement of X-ray

intensities in the specimen

 Data reduction through matrix corrections

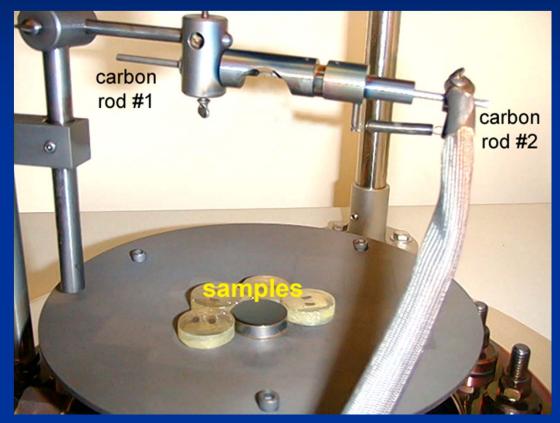
Sample preparation

- Sample cut and mounted in epoxy
- Polished first with coarse SiC paper, then with alumina grit slurry (final size: $\leq 0.25 \ \mu m$)¹
- Washed with water in ultrasonic cleaner ²
- Dried with blow duster and air
- Carbon coated ³
- 1: diamond paste or colloidal silica for some samples; dry polishing paper for water-soluble samples
- 2: ethanol may be used sparingly; cleaned with blow duster and cloth for samples that dissolve in water
- 3: for insulators; if standards are coated, however, all samples must be coated

Carbon coating



Vacuum vapor deposition



To monitor coat-thickness, a polished brass block is coated with the samples



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